

1.0 SCOPE

This specification documents the detail requirements for space qualified product manufactured on Analog Devices, Inc.'s QML certified line per MIL-PRF-38535 Level V except as modified herein. The manufacturing flow described in the STANDARD SPACE LEVEL PRODUCTS PROGRAM brochure is to be considered a part of this specification. <http://www.analog.com/aerospace>. This data sheet specifically details the space grade version of this product. A more detailed operational description and a complete data sheet for commercial product grades can be found at www.analog.com/AD585.

2.0 Part Number. The complete part number(s) of this specification follow:

Part Number	Description
AD585-703M	High Speed, Precision Sample-and-Hold Amplifier
AD585-713M	Radiation Tested, High Speed, Precision Sample-and-Hold Amplifier

2.1 Case Outline.

Letter	Descriptive designator	Case Outline (Lead Finish per MIL-PRF-38535)
M	GDFP1-F14	14-Lead ceramic flat pack (CERPAK)

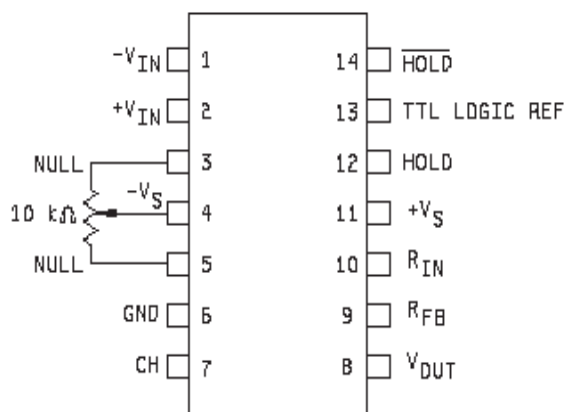


Figure 1 - Terminal connections.

AD585S* Product Page Quick Links

Last Content Update: 08/30/2016

Comparable Parts

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Documentation

Data Sheet

- AD585S: High Speed, Precision Sample-and-Hold Amplifier Aerospace Data Sheet

Design Resources

- AD585S Material Declaration
- PCN-PDN Information
- Quality And Reliability
- Symbols and Footprints

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3.0 Absolute Maximum Ratings. 1/

Supply voltage.....	±18V
Logic inputs	±V _S
Analog inputs.....	±V _S
R _{IN} , R _{FB} pins	±V _S
Output short circuit to ground.....	Indefinite
TTL logic reference short circuit to ground	Indefinite
Storage temperature range	-65°C to +150°C
Ambient operating temperature range (T _A)	-55°C to +125°C
Junction Temperature (T _J)	+150°C
Lead temperature (soldering, 10 seconds)	+300°C

1/ Unless otherwise specified, all voltages are referenced to ground.

3.1 Recommended operating conditions.

Supply voltage range:

+V_S +5V to +18Vdc

-V_S -12V dc to -18V dc

3.2 Thermal Characteristics:

Thermal Resistance, cerpak (M) Package

Junction-to-Case (Θ_{JC}) = 60°/W Max

Junction-to-Ambient (Θ_{JA}) = 140°/W Max

4.0 Electrical Table:

Table I						
Parameter See notes at end of table	Symbol	Conditions <u>1/</u>	Sub-group	Limit Min	Limit Max	Units
Offset voltage	V_{OS}	$V_{OUT} = 0V$	1, 2, 3	-3	3	mV
Bias current	I_B	$V_{IN} = 0V$	1	-2	2	nA
			2	-50	50	
TTL reference output	V_{LREF}	50 μA load	1	1.2	1.6	V
			2, 3	0.8	1.9	
Logic input high voltage	V_{IH}	Hold = V_{LREF}	1	2.0		
			2, 3	2.0		
Logic input low voltage <u>2/</u>	V_{IL}	Hold = V_{LREF}	1		0.8	
			2, 3		0.7	
Logic input current	I_{IL}	$V_S = \pm 18V$	1, 2, 3		50	μA
Supply current	I_{SS}	$R_L = \text{infinite}$	1, 2, 3		10	mA
Power supply rejection	PSRR	+ $V_S = +5V$ to +18V - $V_S = -12V$ to -18V $V_{IN} = V_{OUT} = 0V$	1	70		dB
Acquisition time	T _{acq}	10V step to 0.01%	7		3	μS
		20V step to 0.01% <u>3/</u>			5	
Droop rate <u>2/</u> <u>4/</u>	V_{DRP}	$V_{IN} = 0V$	4		1	mV/mS
Sample to hold offset <u>2/</u>	SH_{OS}	$V_{IN} = 0V$	4	-3	3	mV
Application resistor mismatch	ΔRM		1, 2, 3		0.3	%
Common mode rejection	CMRR	$V_{CM} = \pm 10V$	1	80		dB
			2, 3	77		
Slew current <u>5/</u>	I_{SL}		4	850		μA
			5, 6	600		
Output resistance	R_{OUT}	$I_{OUT} = \pm 10mA$	1		0.05	Ω
			2, 3		0.10	
Output current	I_{OUT}	$R_L = 100\Omega$	1	12		mA

TABLE I NOTES:

- 1/ $V_S = \pm 15V$, C_H = Internal, R_L = Infinite, $A = +1$, Hold active, sample mode unless otherwise noted.
2/ Tested in hold mode.
3/ Guaranteed if not tested to the limits specified.
4/ Doubles every 10°C.
5/ $V_{OUT} = 20V_{p-p}$. Slew rate = slew current/ C_H .

4.1 **Electrical Test Requirements:**

Table II	
Test Requirements	Subgroups (in accordance with MIL-PRF-38535, Table III)
Interim Electrical Parameters	1
Final Electrical Parameters	1, 2, 3, 4, 5, 6 <u>1</u> / <u>2</u> /
Group A Test Requirements	1, 2, 3, 4, 5, 6, 7
Group C end-point electrical parameters	1 <u>2</u> /
Group D end-point electrical parameters	1
Group E end-point electrical parameters	1

1/ PDA applies to Subgroup 1 only. Deltas excluded from PDA

2/ See table III for delta limits.

4.2 **Table III. Burn-in test delta limits.**

Table III			
TEST TITLE	ENDPOINT LIMIT	DELTA LIMIT	UNITS
SHOS	±3	±3	mV

5.0 **Life Test/Burn-In Circuit:**

5.1 HTRB is not applicable for this drawing.

5.2 Burn-in is per MIL-STD-883 Method 1015 test condition D.

5.3 Steady state life test is per MIL-STD-883 Method 1005.

Rev	Description of Change	Date
A	Initiate	6/5/2000
B	Update web address. Paragraph 5.2, change BI condition from B to D. Delete subgroups 5 & 6 from Table II (they are not on Table I) Add subgroup 7 to group A requirements on Table II.	2/14/2002
C	Update web address. Remove burn-in and radiation bias circuits	5/16/2003
D	Add AD585-703M and AD585-713M.	4/4/20005
E	Update header/footer & add to 1.0 scope description.	2/21/2008
F	Add Junction Temperature (T _J).....+150°C to 3.0 Absolute Maximum Ratings	3/31/2008
G	Correct Vos & IsI Subgroup number errors and update Table II.	8/9/2010
H	Remove obsolete part numbers and update ASD to ADI Standard	11/22/2011

